

COMPLIANT

K2560-VB Datasheet N-Channel 200 V (D-S) MOSFET

| PRODUCT SUMMARY | | | | |
|---------------------|---------------------------------|--------------------|--|--|
| V _{DS} (V) | R _{DS(on)} (Ω) | I _D (A) | | |
| 200 | 0.110 at V _{GS} = 10 V | 30 | | |

G D S

Top View

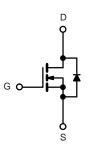
DRAIN connected to TAB

FEATURES

- TrenchFET[®] Power MOSFET
- 175 °C Junction Temperature
- PWM Optimized
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

• Primary Side Switch



N-Channel MOSFET

| ABSOLUTE MAXIMUM RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted) | | | | | | |
|---|-------------------------|-----------------------------------|------------------|------|--|--|
| Parameter | | Symbol | Limit | Unit | | |
| Drain-Source Voltage | | V _{DS} | 200 | - V | | |
| Gate-Source Voltage | V _{GS} | ± 20 | | | | |
| | T _C = 25 °C | - I _D | 30 | | | |
| Continuous Drain Current (T _J = 175 °C) ^b | T _C = 125 °C | | 15 | | | |
| Pulsed Drain Current | I _{DM} | 70 | A | | | |
| Continuous Source Current (Diode Conduction) | ۱ _S | 12 | | | | |
| Avalanche Current | I _{AS} | 12 | | | | |
| Single Pulse Avalanche Energy | L = 0.1 mH | E _{AS} | 20 | mJ | | |
| Maximum Dawar Dissinction | T _C = 25 °C | PD | 126 ^b | w | | |
| Maximum Power Dissipation | T _A = 25 °C | ГD | 3 ^a | | | |
| Operating Junction and Storage Temperature Range | | T _J , T _{stg} | - 55 to 175 | °C | | |

| THERMAL RESISTANCE RATINGS | | | | | | | |
|----------------------------------|--------------|-------------------|---------|---------|------|--|--|
| Parameter | | Symbol | Typical | Maximum | Unit | | |
| | t ≤ 10 s | R _{thJA} | 15 | 18 | °C/W | | |
| Junction-to-Ambient ^a | Steady State | | 40 | 50 | | | |
| Junction-to-Case (Drain) | | R _{thJC} | 0.85 | 1.1 | | | |

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. See SOA curve for voltage derating.



| Parameter | Symbol | Test Conditions | Min. | Typ. ^a | Max. | Unit | |
|---|---------------------|--|------|-------------------|-------|------|--|
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V _{DS} | V _{GS} = 0 V, I _D = 250 μA 200 | | | | V | |
| Gate Threshold Voltage | V _{GS(th)} | $V_{DS} = V_{GS}, I_D = 250 \ \mu A$ | 1 | | 3 | V | |
| Gate-Body Leakage | I _{GSS} | $V_{DS} = 0 V, V_{GS} = \pm 20 V$ | | | ± 100 | nA | |
| | | V _{DS} = 200 V, V _{GS} = 0 V | | | 1 | μA | |
| Zero Gate Voltage Drain Current | I _{DSS} | $V_{DS} = 200 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$ | | | 50 | | |
| | | V _{DS} = 200 V, V _{GS} = 0 V, T _J = 175 °C | | | 250 | | |
| On-State Drain Current ^b | I _{D(on)} | $V_{DS} = 5 V, V_{GS} = 10 V$ | 40 | | | А | |
| | | $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}$ | | 0.110 | 0.125 | 0 | |
| | D | $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}, \text{ T}_{J} = 125 \text{ °C}$ | | 0.120 | 0.140 | | |
| Drain-Source On-State Resistance ^b | R _{DS(on)} | $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}, \text{ T}_{J} = 175 \text{ °C}$ | | 0.130 | 0.150 | Ω | |
| | | $V_{GS} = 4.5 \text{ V}, I_D = 3 \text{ A}$ | | 0.132 | 0.152 | | |
| Forward Transconductance ^b | 9 _{fs} | V _{DS} = 15 V, I _D = 3 A | | 35 | | S | |
| Dynamic ^a | | | | | | | |
| Input Capacitance | C _{iss} | | | 1800 | | pF | |
| Output Capacitance | C _{oss} | V_{GS} = 0 V, V_{DS} = 25 V, F = 1 MHz | | 180 | | | |
| Reverse Transfer Capacitance | C _{rss} | | | 80 | | | |
| Total Gate Charge ^c | Qg | | | 34 | 51 | | |
| Gate-Source Charge ^c | Q _{gs} | V_{DS} = 100 V, V_{GS} = 10 V, I_{D} = 3 A | | 8 | | nC | |
| Gate-Drain Charge ^c | Q _{gd} | | | 12 | | | |
| Gate Resistance | R _g | | 0.5 | | 2.9 | Ω | |
| Turn-On Delay Time ^c | t _{d(on)} | | | 15 | 25 | | |
| Rise Time ^c | t _r | V_{DD} = 100 V, R _L = 5.2 Ω | | 50 | 75 | ns | |
| Turn-Off Delay Time ^c | t _{d(off)} | $I_D \cong$ 3 A, V_{GEN} = 10 V, R_g = 2.5 Ω | | 30 | 45 | | |
| Fall Time ^c | t _f | | | 60 | 90 | | |
| Source-Drain Diode Ratings and Chara | acteristics (1 | Γ _C = 25 °C) | | | | | |
| Pulsed Current | I _{SM} | | | 1 | 30 | А | |
| Diode Forward Voltage ^b | V _{SD} | I _F = 3 A, V _{GS} = 0 V | | 0.9 | 1.5 | V | |
| Source-Drain Reverse Recovery Time | t _{rr} | I _F = 3 A, dl/dt = 100 A/μs | | 180 | 250 | ns | |

Notes:

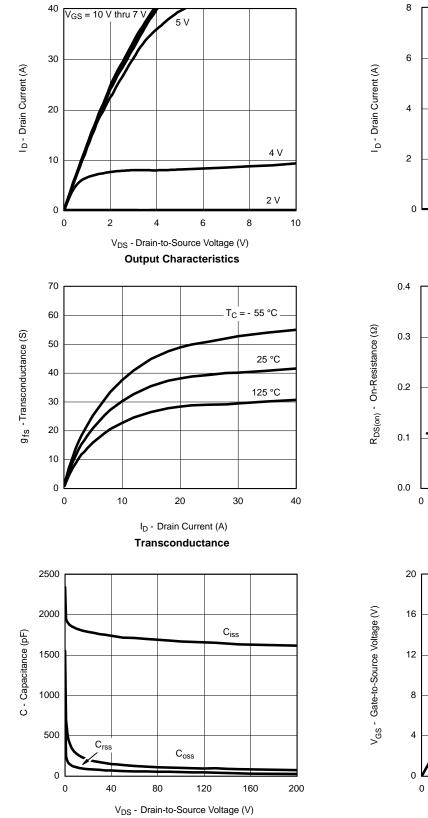
a. Guaranteed by design, not subject to production testing.

b. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

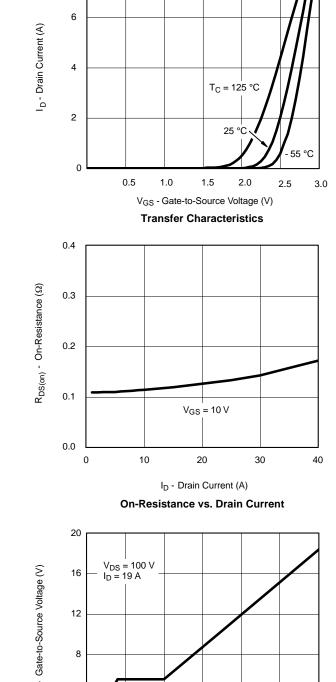
c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



10

20

30

Qg - Total Gate Charge (nC)

Gate Charge

40



60

50



T_J = 25 °C

0.9

10 µs

T T H 100 µs

ms

10 ms <u>++++t</u>

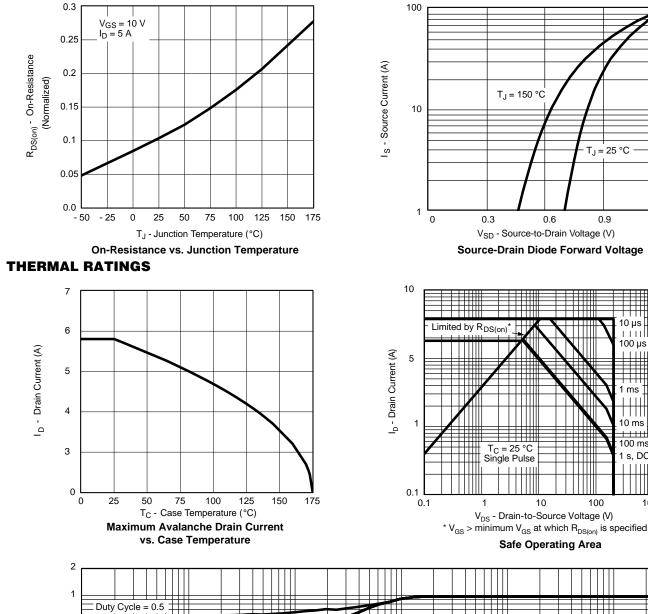
100 ms

1 s, DC 1111

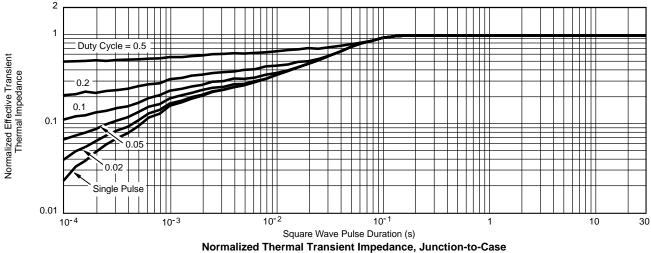
1000

100

1.2

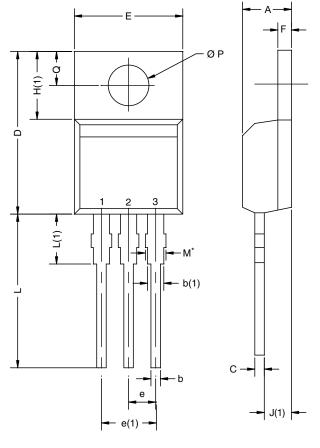


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





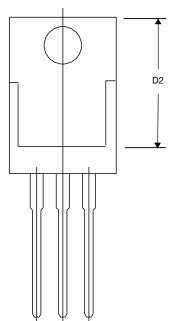
TO-220AB



| | MILLIN | IETERS | INCHES | | |
|--|--------|--------|--------|-------|--|
| DIM. | MIN. | MAX. | MIN. | MAX. | |
| А | 4.25 | 4.65 | 0.167 | 0.183 | |
| b | 0.69 | 1.01 | 0.027 | 0.040 | |
| b(1) | 1.20 | 1.73 | 0.047 | 0.068 | |
| С | 0.36 | 0.61 | 0.014 | 0.024 | |
| D | 14.85 | 15.49 | 0.585 | 0.610 | |
| D2 | 12.19 | 12.70 | 0.480 | 0.500 | |
| E | 10.04 | 10.51 | 0.395 | 0.414 | |
| е | 2.41 | 2.67 | 0.095 | 0.105 | |
| e(1) | 4.88 | 5.28 | 0.192 | 0.208 | |
| F | 1.14 | 1.40 | 0.045 | 0.055 | |
| H(1) | 6.09 | 6.48 | 0.240 | 0.255 | |
| J(1) | 2.41 | 2.92 | 0.095 | 0.115 | |
| L | 13.35 | 14.02 | 0.526 | 0.552 | |
| L(1) | 3.32 | 3.82 | 0.131 | 0.150 | |
| ØР | 3.54 | 3.94 | 0.139 | 0.155 | |
| Q | 2.60 | 3.00 | 0.102 | 0.118 | |
| ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471 | | | | | |

Note

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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